



BSI Standards Publication

Semiconductor devices – Semiconductor interface for automotive vehicles

Part 1: General requirements of power interface for automotive vehicle sensors (IEC 62969-1:2017)

National foreword

This British Standard is the UK implementation of EN IEC 62969-1:2018. It is identical to IEC 62969-1:2017.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its secretary.

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English Version

Semiconductor devices - Semiconductor interface for automotive vehicles - Part 1: General requirements of power interface for automotive vehicle sensors
(IEC 62969-1:2017)

Dispositifs à semiconducteurs - Interface à semiconducteurs pour les véhicules automobiles - Partie 1 : Exigences générales de l'interface d'alimentation destinée aux capteurs des véhicules automobiles
(IEC 62969-1:2017)

Halbleiterbauelemente - Halbleiterschnittstelle für Automobile - Teil 1: Allgemeine Anforderungen an Energie-Schnittstellen für Automobil-Sensoren
(IEC 62969-1:2017)

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European Committee for Electrotechnical Standardization
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European foreword

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document have to be withdrawn

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The text of the International Standard IEC 62969-1:2017 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following note has to be added for the standard indicated:

IEC 61508 (all parts) NOTE Harmonized as EN 61508 (all parts).

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60068-2-1	-	Environmental testing -- Part 2-1: Tests - Test A: Cold	EN 60068-2-1	-
IEC 60068-2-2	-	Environmental testing -- Part 2-2: Tests - Test B: Dry heat	EN 60068-2-2	-
IEC 60068-2-14	-	Environmental testing -- Part 2-14: Tests - Test N: Change of temperature	EN 60068-2-14	-
IEC 60068-2-30	-	Environmental testing -- Part 2-30: Tests - Test Db: Damp heat, cyclic (12 h + 12 h cycle)	EN 60068-2-30	-
IEC 60529	-	Degrees of protection provided by enclosures (IP Code)	-	-
IEC 60721	series	Classification of environmental conditions - Part 1: Environmental parameters and their severities	EN 60721	series
IEC 60749-10	-	Semiconductor devices - Mechanical and climatic test methods -- Part 10: Mechanical shock	EN 60749-10	-
IEC 60749-12	-	Semiconductor devices - Mechanical and climatic test methods - Part 12: Vibration, variable frequency	EN 60749-12	-
IEC 61851-1	-	Electric vehicle conductive charging system -- Part 1: General requirements	-	-
IEC 61967-1	-	Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz - Part 1: General conditions and definitions	-	-
IEC 61967-2	-	Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz -- Part 2: Measurement of radiated emissions - TEM cell and wideband TEM cell method	EN 61967-2	-
IEC TS 61967-3	-	Integrated circuits - Measurement of electromagnetic emissions - Part 3: Measurement of radiated emissions - Surface scan method	-	-

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IEC 61967-4	-	Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz -- Part 4: Measurement of conducted emissions - 1 ohm/150 ohm direct coupling method	EN 61967-4	-
IEC 61967-5	-	Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz -- Part 5: Measurement of conducted emissions - Workbench Faraday Cage method	EN 61967-5	-
IEC 61967-6	-	Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz -- Part 6: Measurement of conducted emissions - Magnetic probe method	EN 61967-6	-
IEC 61967-8	-	Integrated circuits - Measurement of electromagnetic emissions -- Part 8: Measurement of radiated emissions - IC stripline method	EN 61967-8	-
IEC 62132-1	-	Integrated circuits - Measurement of electromagnetic immunity - Part 1: General conditions and definitions	EN 62132-1	-
IEC 62132-2	-	Integrated circuits - Measurement of electromagnetic immunity -- Part 2: Measurement of radiated immunity - TEM cell and wideband TEM cell method	EN 62132-2	-
IEC 62132-3	-	Integrated circuits - Measurement of electromagnetic immunity, 150 kHz to 1 GHz -- Part 3: Bulk current injection (BCI) method	EN 62132-3	-
IEC 62132-4	-	Integrated circuits - Measurement of electromagnetic immunity, 150 kHz to 1 GHz -- Part 4: Direct RF power injection method	EN 62132-4	-
IEC 62132-5	-	Integrated circuits - Measurement of electromagnetic immunity, 150 kHz to 1 GHz -- Part 5: Workbench Faraday cage method	EN 62132-5	-
IEC TS 61967-3	-	Integrated circuits - Measurement of electromagnetic emissions - Part 3: Measurement of radiated emissions - Surface scan method	-	-
IEC 62262	-	Degrees of protection provided by enclosures for electrical equipment against external mechanical impacts (IK code)	EN 62262	-

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